

[54] CRYSTAL GROWING

[75] Inventors: Frederick Schmid, Marblehead;
Chandra P. Khattak, Danvers, both
of Mass.

[73] Assignee: Crystal Systems Inc., Salem, Mass.

[21] Appl. No.: 967,114

[22] Filed: Dec. 7, 1978

[51] Int. Cl.³ C30B 9/04; C30B 11/00;
C30B 15/00

[52] U.S. Cl. 156/600; 156/616 R;
156/617 SP; 156/DIG. 64; 156/DIG. 83

[58] Field of Search 156/DIG. 83, DIG. 64,
156/608, 617 R, 617 M, 617 V, 617 SP, 600,
616 R, 616 A; 422/248

[56] References Cited

U.S. PATENT DOCUMENTS

3,265,528 8/1966 Bond 156/DIG. 83

Primary Examiner—Frank Sever

[57] ABSTRACT

In the growing of crystals, the formation of carbide contaminants is prevented by eliminating direct silica-graphite contact.

13 Claims, 2 Drawing Figures

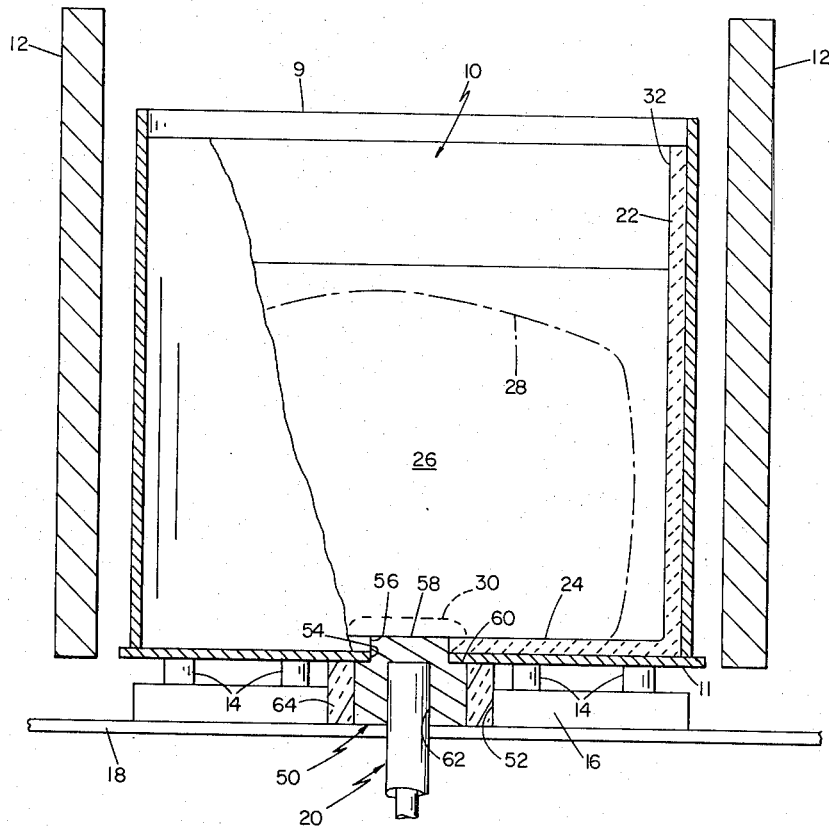


FIG 1

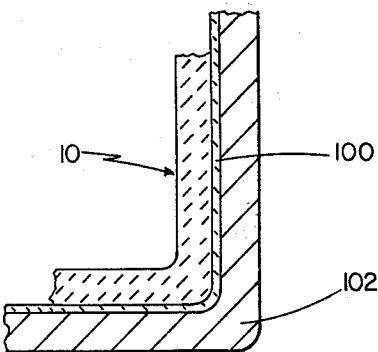
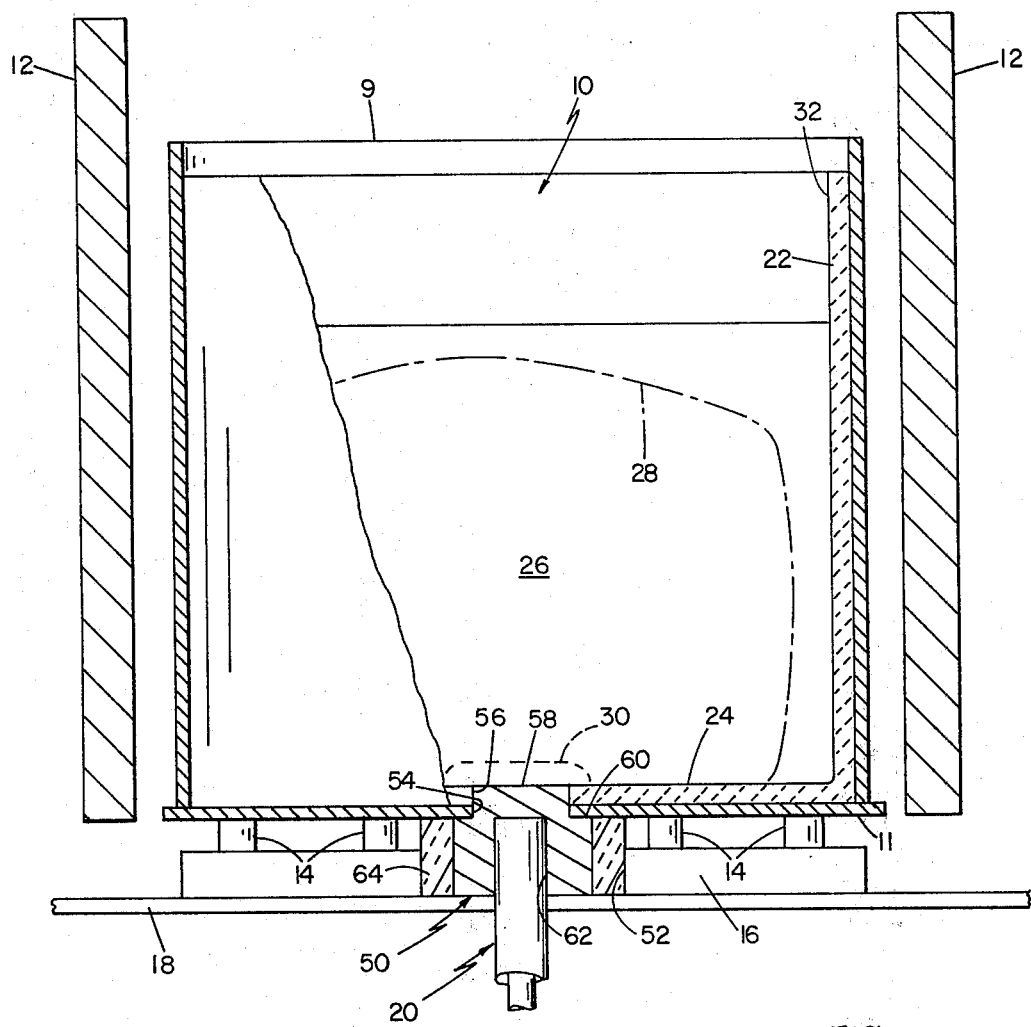


FIG 2

CRYSTAL GROWING

The invention described herein was made in the performance of work under NASA Contract Number NAS 7-100, JPL No. 954,373 and is subject to the provisions of Section 305 of the National Aeronautics and Space Act of 1958 (72 Stat. 435; 42 U.S.C. 2457).

FIELD OF THE INVENTION

This invention relates to growing crystals, particularly of silicon, in vacuum environment.

BACKGROUND OF THE INVENTION

In the past, silicon crystals have been grown from the melt using both the well-known Czochralski crystal growth process and, more recently, the Heat Exchanger Method of crystal growth described in U.S. Pat. Nos. 3,653,432 and 3,898,051 (both of which patents are hereby incorporated by reference). In such processes, serious problems of silicon carbide impurity have been encountered when attempting to grow crystals at pressures below about 30 torr.

SUMMARY OF THE INVENTION

It has been discovered that, at pressures below about 30 torr and at the relatively high temperatures present during crystal growth, (for silicon, typically above 1685° K.), the silica crucible and surrounding graphite retainer generally used in silicon crystal growth react to form carbon monoxide (CO). The gaseous carbon monoxide is transported into the crucible where it contacts the silicon and forms silicon carbide (SiC), since silicon carbide is more stable than carbon monoxide. The unwanted silicon carbide contaminant can cause breakdown of crystallinity and incorporate carbon in silicon. The problem of carbon monoxide formation will be present whenever silica and graphite (carbon) are in contact; and unwanted carbide contaminants will result if the carbide of the crystal being grown is more stable than carbon monoxide.

It has further been discovered that the problem of unwanted carbide contaminants can be overcome by using molybdenum or some other refractory material that is free of elemental carbon, in place of graphite, to support the silica crucible or between the silica crucible and graphite retainer; or by coating the exterior of the crucible or interior of the retainer with refractory material. Either makes it possible to avoid direct silica-graphite (carbon) contact within the furnace.

DESCRIPTION OF THE PREFERRED EMBODIMENT

Objects, features and advantages of the invention will appear from the following detailed description of the structure and use of a preferred practice thereof, taken together with the attached drawing in which:

FIG. 1 is a schematic view, partially in section, of a crucible, molybdenum retainer, conducting graphite plug, and insulation within the heating chamber of a casting furnace; and

FIG. 2 is a view of portions of a modified embodiment.

Referring now to FIG. 1, it illustrates a silica crucible 10 within the cylindrical heating chamber defined by the resistance heater 12 of a casting furnace of the type disclosed in U.S. Pat. No. 3,898,051. The crucible 10 rests on a molybdenum disc 11 which itself is supported

by graphite rods 14 mounted on a graphite support plate 16 on the bottom 18 of the heating chamber, and is surrounded by a cylindrical molybdenum retainer 9. A helium cooled molybdenum heat exchanger 20, of the type disclosed in U.S. Pat. No. 3,653,432, extends through openings in the center of the plate 16 and bottom 18.

Crucible 10 is about 6 in. (15 cm.) in height and diameter and its cylindrical wall 22 and base 24 are 0.15 in. (3.7 mm.) thick. Molybdenum disc 11 is about 0.040 in. (1 mm.) thick, and molybdenum retainer 9, comprising a sheet of the same thickness rolled into cylindrical form, engages the exterior of cylinder wall 22. A silicon ingot 26, partially solidified according to the process described in aforementioned U.S. Pat. No. 3,898,051 is shown within the crucible. The solid-liquid interface 28 has advanced from the seed (shown in dashed lines at 30) so that there is a thin annulus of liquid between it and the crucible wall (the temperature of which is above the melting point of silicon), and also liquid above it. When substantially all the liquid has been solidified, the temperature of the crucible wall will be permitted to drop below the silicon melting temperature, and the crucible and solidified ingot will then be cooled.

A stepped cylindrical graphite plug 50 (upper portion diameter 1.9 in., and lower portion diameter 2.5 in.) extends from bottom 18 upwardly through coaxial holes 52, 54, 56 in, respectively, plate 16, molybdenum disc 11 and crucible base 24. The top 58 of plug 50 is flush with the inside bottom surface of crucible base 24. The seen 30 is placed over the plug 50 and the adjacent portion of crucible bottom 24 so as to cover opening 56. The exterior of the plug upper portion fits loosely in openings 54, 56 to allow for thermal expansion; and the step 60 between the plug's upper smaller diameter and lower larger diameter portions engages the underside of plate 11. A small quantity of silicon powder is placed in the area of opening 56 where seed 30, crucible 10 and graphite plug 50 are in proximity. Heat exchanger 20 fits within a coaxial recess 62 in the bottom of plug 50, with the top of the heat exchanger about 1/8 in. below the top 58 of the plug. A graphite felt insulation and/or molybdenum heat shield sleeve 64 closely surrounds the larger diameter portion of plug 50, extending axially of the plug the full distance between bottom 18 and plate 11. As shown, the exterior surface of insulation sleeve 64 engages the interior of opening 52.

During crystal growth, the furnace heating chamber is evacuated to between 0.01 to 1 torr, and heated to between 1685° K. and 1735° K. At these temperatures and pressures, it has been found that any carbon (for example, a graphite crucible retainer) and silica (for example, a crucible) in direct contact will react to form gaseous carbon monoxide, CO, which occurs as per the following reactions:



Each of these reactions is both pressure and temperature dependent. In the range of pressures and temperatures encountered in silicon crystal growth, the pressures of reactions (1) and (2) are, respectively:

$$\log P = 11.62 - 1.57 \times 10^4/T \quad (3)$$